AMENDMENTS TO THE CLAIMS:

Please cancel claims 1-13, without prejudice or disclaimer of their subject matter, and add new claims 22-32, as indicated below. This listing of claims will replace all prior versions and listings of claims in the application:

LISTING OF CLAIMS:

1.-13. (Canceled)

14. (Withdrawn) A method of manufacturing a semiconductor device, comprising:

forming an isolation region in a semiconductor substrate to provide an N- and a P-channel MISFET regions each surrounded by the isolation region;

forming an insulating film on the semiconductor substrate;

forming a conductive film on the insulating film;

patterning selectively the conductive film to provide a gate region in each of the MISFET regions;

forming source and drain regions in each of the MISFET regions for the patterned conductive film by a self-alignment way;

forming a sidewall insulating film around the patterned conductive film;

removing the conductive film and the insulating film of the gate region to provide a space region surrounded by the sidewall insulating film;

forming a gate insulating film on the N- and P-channel MISFET regions each surrounded by the space region, respectively;

forming a first metal silicide film on the gate insulating film within the space region to provide a first gate electrode film;

forming a metal film different from metal composing the first metal silicide film on the P-channel MISFET region; and

heat-treating the semiconductor substrate to form a second gate electrode film formed by a solid phase reaction between the first metal silicide film and the metal film, the second gate electrode film being composed of a second metal silicide made of a second metal material different from a first metal material composing the first metal silicide.

15. (Withdrawn) The method according to claim 14, wherein the second gate electrode film is formed by changing into a film including at least one material selected from the first metal material and a third metal silicide, the third metal silicide having the same constituent material of the first metal silicide and lower silicon content than the first metal silicide.

16. (Withdrawn) The method according to claim 14, wherein the number of silicon atoms per unit volume is 2.5 times more than the number of metal atoms per unit volume in a composition ratio between silicon and metal composing the first metal silicide.

17. (Withdrawn) The method according to claim 14, wherein the number of silicon atoms per unit volume is not more than the number of metal atoms per unit volume in the composition ratio between silicon and metal composing the third metal silicide.

18. (Withdrawn) The method according to claim 14, wherein a tungsten silicide film is formed as the first metal silicide.

19. (Withdrawn) The method according to claim 14, wherein the second metal silicide is composed of at least one kind of metal silicide selected from the metal silicides of platinum, palladium, and rhodium.

20. (Withdrawn) The method according to claim 14, wherein one material selected from the metal film and the metal silicide film is formed on the source and drain regions of the N- and P-channel MISFETs during a process for forming the sidewall insulating film and the space region.

21. (Withdrawn) The method according to claim 14, wherein a process for forming one material selected from the metal film and the metal silicide film on the source and drain regions of the N- and P-channel MISFETs is carried out after the heat treatment.

22. (New) A semiconductor device comprising:

a semiconductor substrate;

an N-channel MISFET and a P-channel MISFET provided on the semiconductor substrate, each of the N- and P-channel MISFETs being isolated by an isolation region and having a gate insulating film;

a first gate electrode film provided on the gate insulating film of the N-channel MISFET, the first gate electrode film being comprised of a first metal silicide composed of a first metal material;

a second gate electrode film provided on the gate insulating film of the P-channel MISFET, the second gate electrode film being comprised of a second metal silicide and a third metal silicide, the second metal silicide being comprised of a second metal material different from the first metal material, the third metal silicide including the first metal material and having a lower silicon content than the first metal silicide; and

the first gate electrode film having a work function being lower than that of the second gate electrode film.

23. (New) The semiconductor device according to claim 22, wherein the second gate electrode film further includes the first metal material which is not silicified.

24. (New) The semiconductor device according to claim 22, wherein one material selected from the first metal material and the third metal silicide is presented in a form of a particle.

25. (New) The semiconductor device according to claim 22, wherein the gate insulating film is comprised of a hafnium oxide film.

26. (New) The semiconductor device according to claim 22, wherein the first metal material is comprised of one material selected from tungsten, molybdenum, titanium, zirconium, hafnium, tantalum and niobium.

27. (New) The semiconductor device according to claim 22, wherein the second metal material is comprised of one material selected from platinum, palladium and rhodium.

28. (New) The semiconductor device according to claim 22, wherein a number of silicon atoms per unit volume is 2.5 times more than a number of metal atoms per unit volume in a composition ratio between silicon and metal composing the first metal silicide.

29. (New) A semiconductor device comprising:

a semiconductor substrate;

an N-channel MISFET and a P-channel MISFET provided on the semiconductor substrate, each of the N- and P-channel MISFETs being isolated by an isolation region and having a gate insulating film, elevated source/drain regions composed of a semiconductor film being provided on extension regions of the N-channel MISFET and the P-channel MISFET;

a first gate electrode film provided on the gate insulating film of the N-channel MISFET, the first gate electrode film being comprised of a first metal silicide composed of a first metal material;

a second gate electrode film provided on the gate insulating film of the P-channel MISFET, the second gate electrode film being comprised of a second metal silicide and a third metal silicide, the second metal silicide being comprised of a second metal material different

from the first metal material, the third metal silicide including the first metal material and having a lower silicon content than the first metal silicide; and

the first gate electrode film having a work function lower than that of the second gate electrode film.

30. (New) The semiconductor device according to claim 29, wherein a metal silicide film is provided on each of the elevated source/drain regions.

31. (New) The semiconductor device according to claim 29, wherein a metal silicide film is provided on each of the elevated source/drain regions and the first and second gate electrodes.

32. (New) The semiconductor device according to claim 31, wherein the metal silicide film is made of a nickel silicide film.